

QUADRUPLE 2-INPUT POSITIVE NAND GATE
WITH OPEN COLLECTOR OUTPUT

DESCRIPTION

The M74LS03P is a semiconductor integrated circuit containing four dual-input positive-logic NAND gates with open collector outputs, usable as negative-logic NOR gates.

FEATURES

- Usable in AND-Tie connection
- High breakdown input voltage ($V_I \geq 15V$)
- High breakdown output voltage ($V_O \geq 7V$)
- Low power dissipation ($P_d = 8mW$ typical)
- High speed ($t_{pd} = 10ns$ typical)
- Wide operating temperature range ($T_a = -20 \sim +75^{\circ}C$)

APPLICATION

General purpose, for use in industrial and consumer equipment.

FUNCTIONAL DESCRIPTION

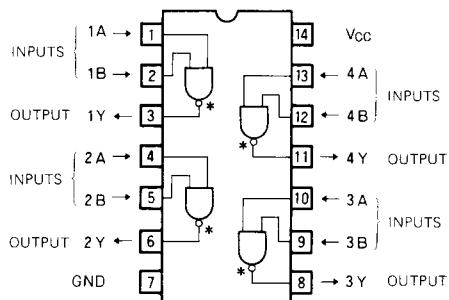
With use of open collector outputs and SBD inputs featuring a high breakdown voltage, the high-level output impedance can be selected freely by use of an external load resistor. This permits wire-AND connection which has been impossible with conventional gates.

When inputs A and B are high, output Y is low and when one or both inputs are low, the output Y is high.

FUNCTION TABLE

A	B	Y
L	L	H
H	L	H
L	H	H
H	H	L

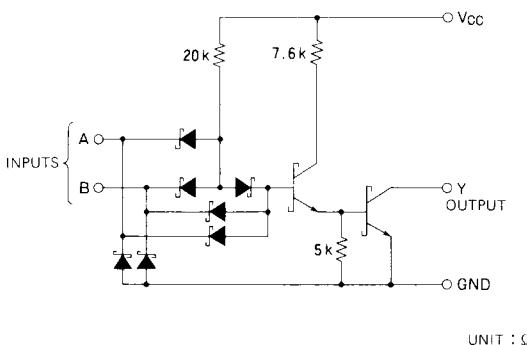
PIN CONFIGURATION (TOP VIEW)



* : OPEN COLLECTOR OUTPUT

Outline 14P4

CIRCUIT SCHEMATIC (EACH GATE)



UNIT : Ω

ABSOLUTE MAXIMUM RATINGS ($T_a = -20 \sim +75^{\circ}C$, unless otherwise noted)

Symbol	Parameter	Conditions	Limits	Unit
V_{CC}	Supply voltage		-0.5 ~ +7	V
V_I	Input voltage		-0.5 ~ +15	V
V_O	Output voltage	High-level state	-0.5 ~ +7	V
T_{opr}	Operating free-air ambient temperature range		-20 ~ +75	°C
T_{stg}	Storage temperature range		-65 ~ +150	°C

QUADRUPLE 2-INPUT POSITIVE NAND GATE
WITH OPEN COLLECTOR OUTPUTRECOMMENDED OPERATING CONDITIONS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V_{CC}	Supply voltage	4.75	5	5.25	V
I_{OH}	High-level output current	$V_O = 5.5\text{V}$	0	100	μA
I_{OL}	$V_{OL} \leq 0.4\text{V}$	0		4	mA
	$V_{OL} \leq 0.5\text{V}$	0		8	mA

ELECTRICAL CHARACTERISTICS ($T_a = -20 \sim +75^\circ\text{C}$, unless otherwise noted)

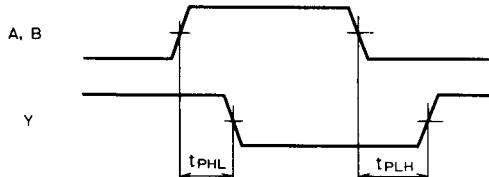
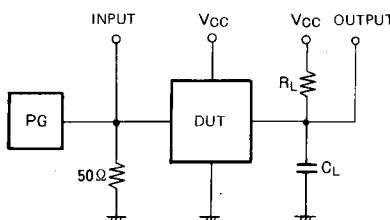
Symbol	Parameter	Test conditions			Limits			Unit
		Min	Typ	Max	Min	Typ	Max	
V_{IH}	High-level input voltage				2			V
V_{IL}	Low-level input voltage						0.8	V
V_{IC}	Input clamp voltage	$V_{CC}=4.75\text{V}$, $I_{IO}=-18\text{mA}$					-1.5	V
I_{OH}	High-level output current	$V_{CC}=4.75\text{V}$, $V_I=0.8\text{V}$ $V_O=5.5\text{V}$					100	μA
V_{OL}	Low-level output voltage	$V_{CC}=4.75\text{V}$	$I_{OL}=4\text{mA}$		0.25	0.4		V
		$V_I=2\text{V}$	$I_{OL}=8\text{mA}$		0.35	0.5		V
I_{IH}	High-level input current	$V_{CC}=5.25\text{V}$, $V_I=2.7\text{V}$					20	μA
		$V_{CC}=5.25\text{V}$, $V_I=10\text{V}$					0.1	mA
I_{IL}	Low-level input current	$V_{CC}=5.25\text{V}$, $V_I=0.4\text{V}$					-0.4	mA
I_{COH}	Supply current, all inputs high	$V_{CC}=5.25\text{V}$, $V_I=0\text{V}$			0.8	1.6		mA
I_{COL}	Supply current, all outputs low	$V_{CC}=5.25\text{V}$, $V_I=4.5\text{V}$			2.4	4.4		mA

*: All typical values are at $V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$ SWITCHING CHARACTERISTICS ($V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test conditions			Limits			Unit
		Min	Typ	Max	Min	Typ	Max	
t_{PLH}	Low-to-high-level/high-to-low-level output propagation time	$R_L = 2\text{k}\Omega$			10	32		ns
t_{PHL}		$C_L = 15\text{pF}$ (Note 1)			10	28		ns

Note 1: Measurement circuit

TIMING DIAGRAM (Reference level = 1.3V)



(1) The pulse generator (PG) has the following characteristics:

 $\text{PRR} = 1\text{MHz}$, $t_r = 6\text{ns}$, $t_f = 6\text{ns}$, $t_w = 500\text{ns}$, $V_p = 3V_{p.p.}$, $Z_0 = 50\Omega$ (2) C_L includes probe and jig capacitance.

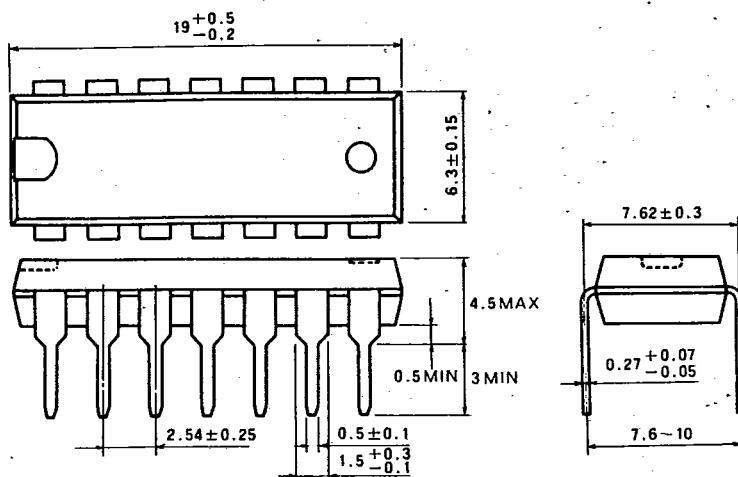
MITSUBISHI LSTTLs
PACKAGE OUTLINES

MITSUBISHI {DGTL LOGIC} 07E D | 6249827 0013561 3

T-90-20

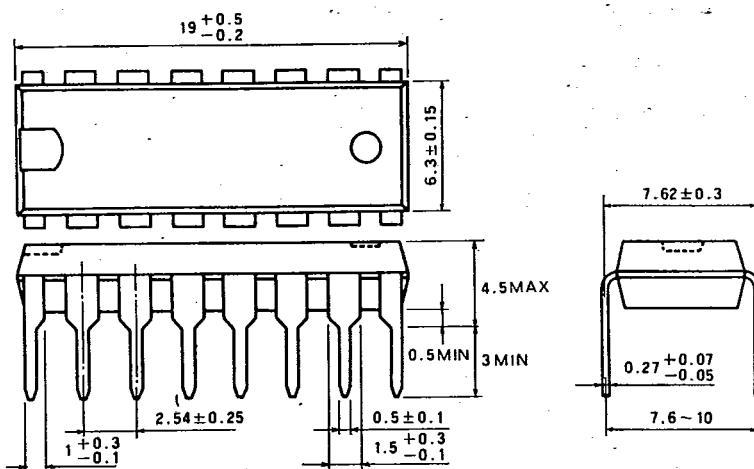
TYPE 14P4 14-PIN MOLDED PLASTIC DIL

Dimension in mm



TYPE 16P4 16-PIN MOLDED PLASTIC DIL

Dimension in mm



TYPE 20P4 20-PIN MOLDED PLASTIC DIL

Dimension in mm

